

CHEMPLEX, XRF Sample Cup Thin-Film Sample Support Windows, Thickness 1.5 µm, Roll 76.2 mm, Etnom

Art. ID	CX-95
Unit	91,4 m
Deliverydetails	No Dangerous Good /not restricted

Description

Etnom® was the first thin - film substance to chemically resist attack by aliphatic and especially aromatic hydrocarbons and have the unique characteristic of contracting when exposed to petrochemical hydrocarbons. This unique characteristic allows the thin film to remain taut when exposed to samples containing these hydrocarbons and maintain a consistent taut flat sample support window plane during the entire integration time of analysis. Etnom® is available in a variety of thicknesses ranging from 1.5 through 3.0 µm, it is frequently used and ideally suitable for sulfur analysis in aliphatic and particularly aromatic hydrocarbons. 2.0, 2.5 and 3.0 µm Etnom® thin - films are limited in availability only to SpectroMembrane® Carrier Frames.